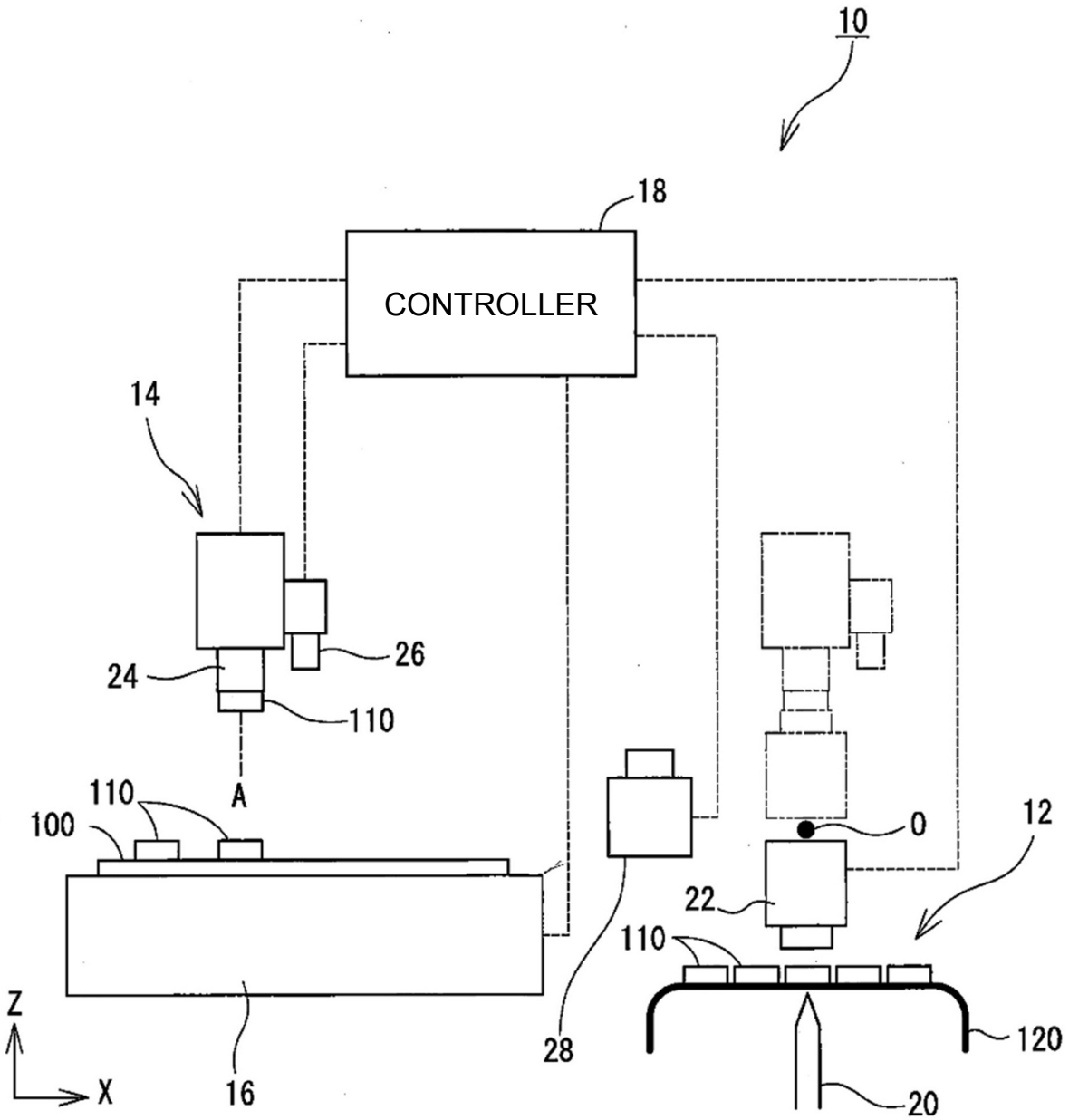

FIG. 1

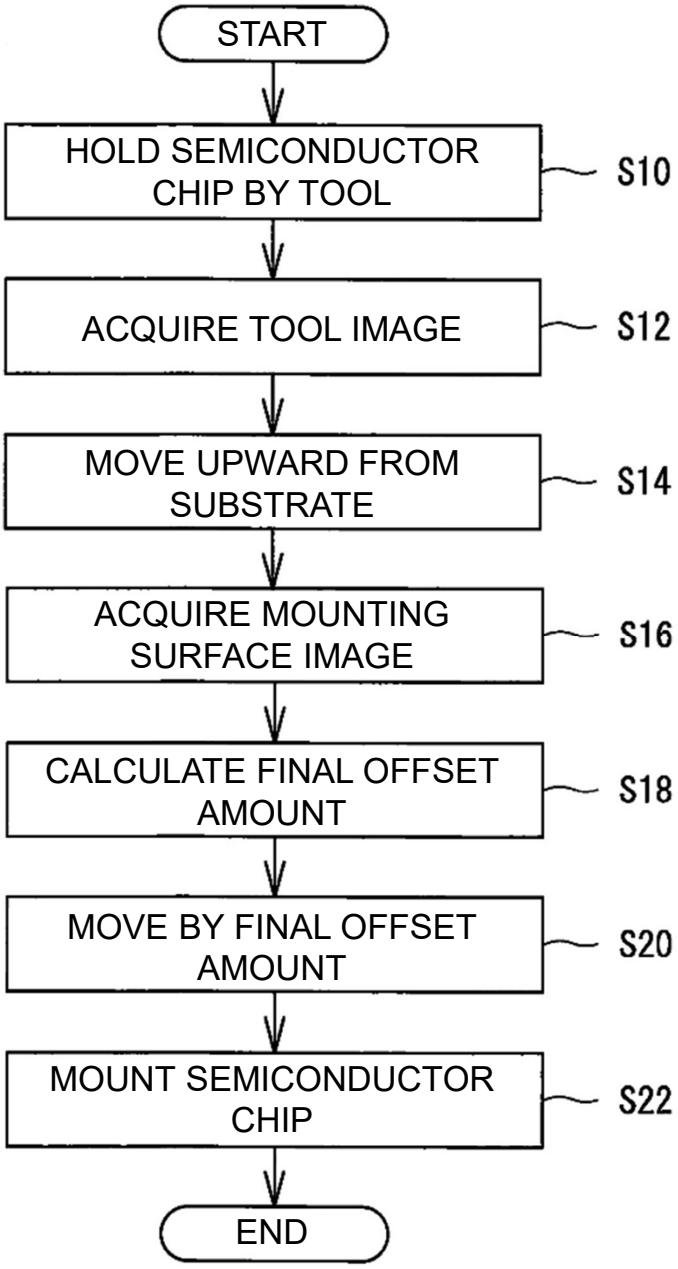
START
HOLD SEMICONDUCTOR CHIP BY TOOL
S10
ACQUIRE TOOL IMAGE
S12
MOVE UPWARD FROM SUBSTRATE
S14
ACQUIRE MOUNTING SURFACE IMAGE
S16
CALCULATE FINAL OFFSET AMOUNT
S18
MOVE BY FINAL OFFSET AMOUNT
S20
MOUNT SEMICONDUCTOR CHIP
S22
END

FIG. 2

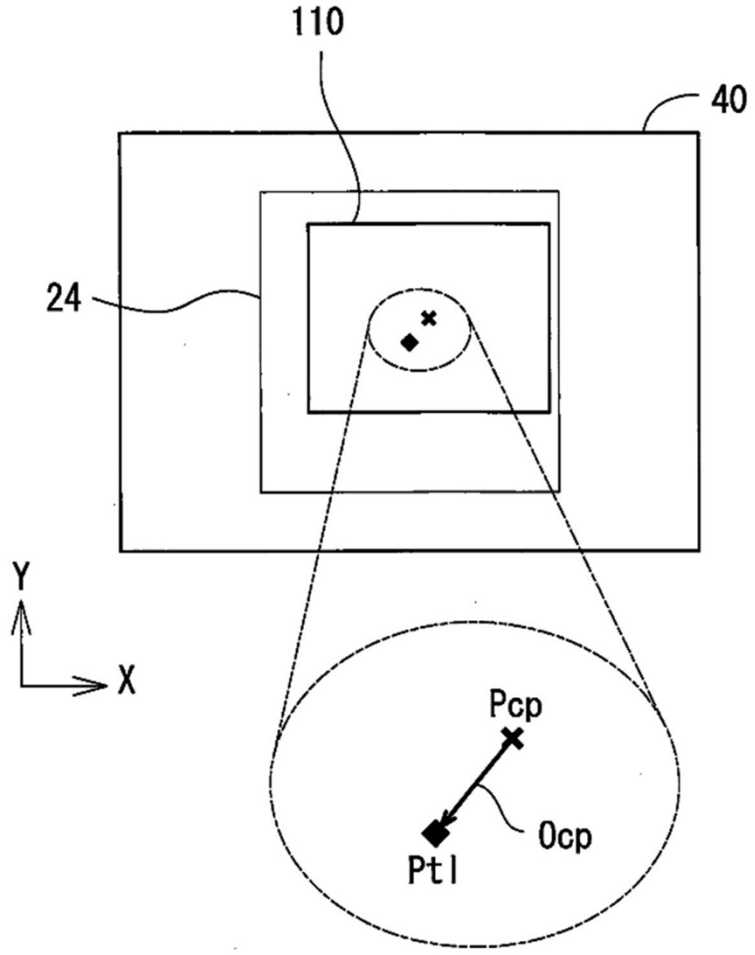

FIG. 3

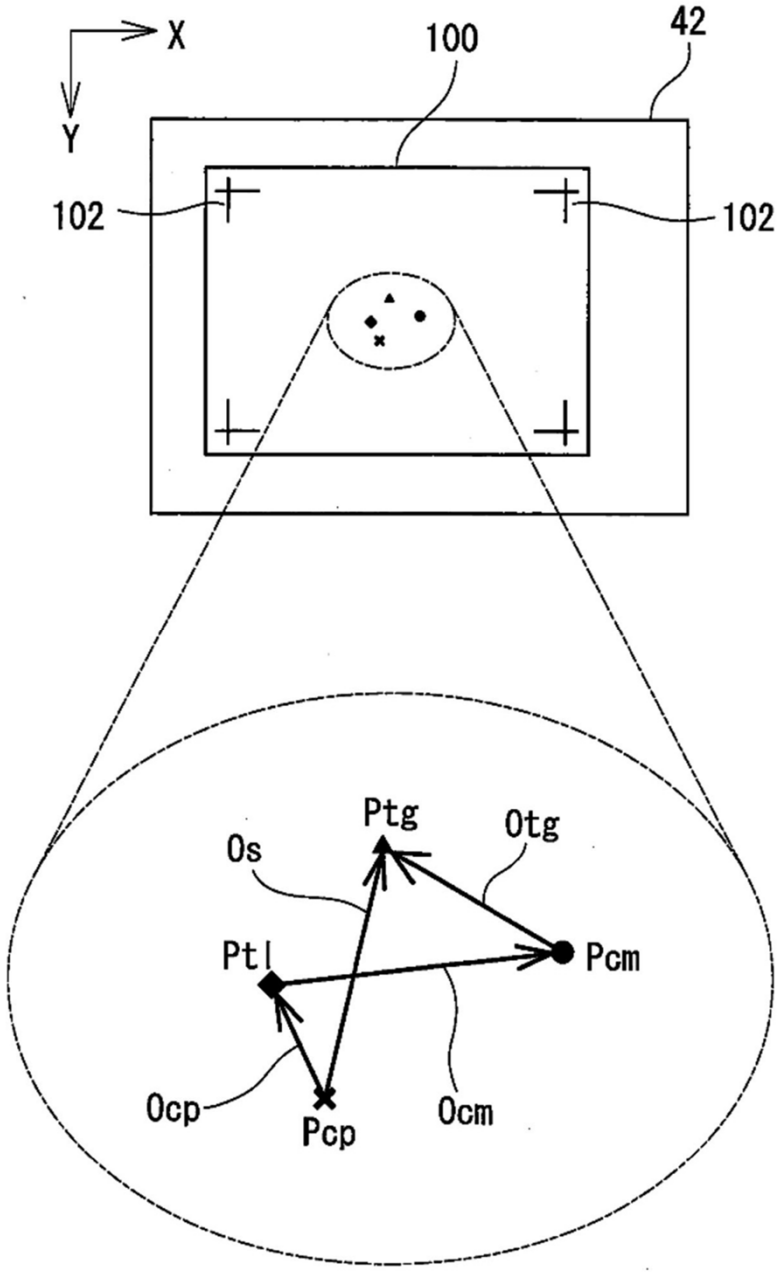

FIG. 4

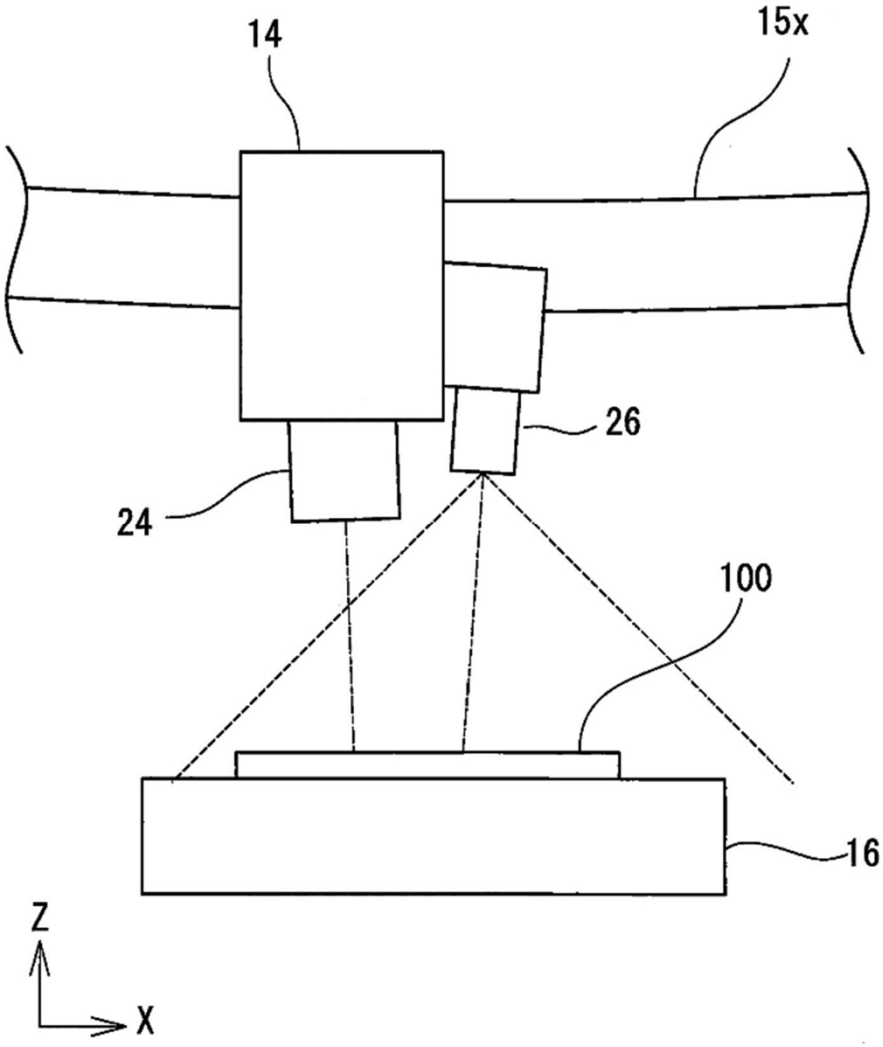

FIG. 5

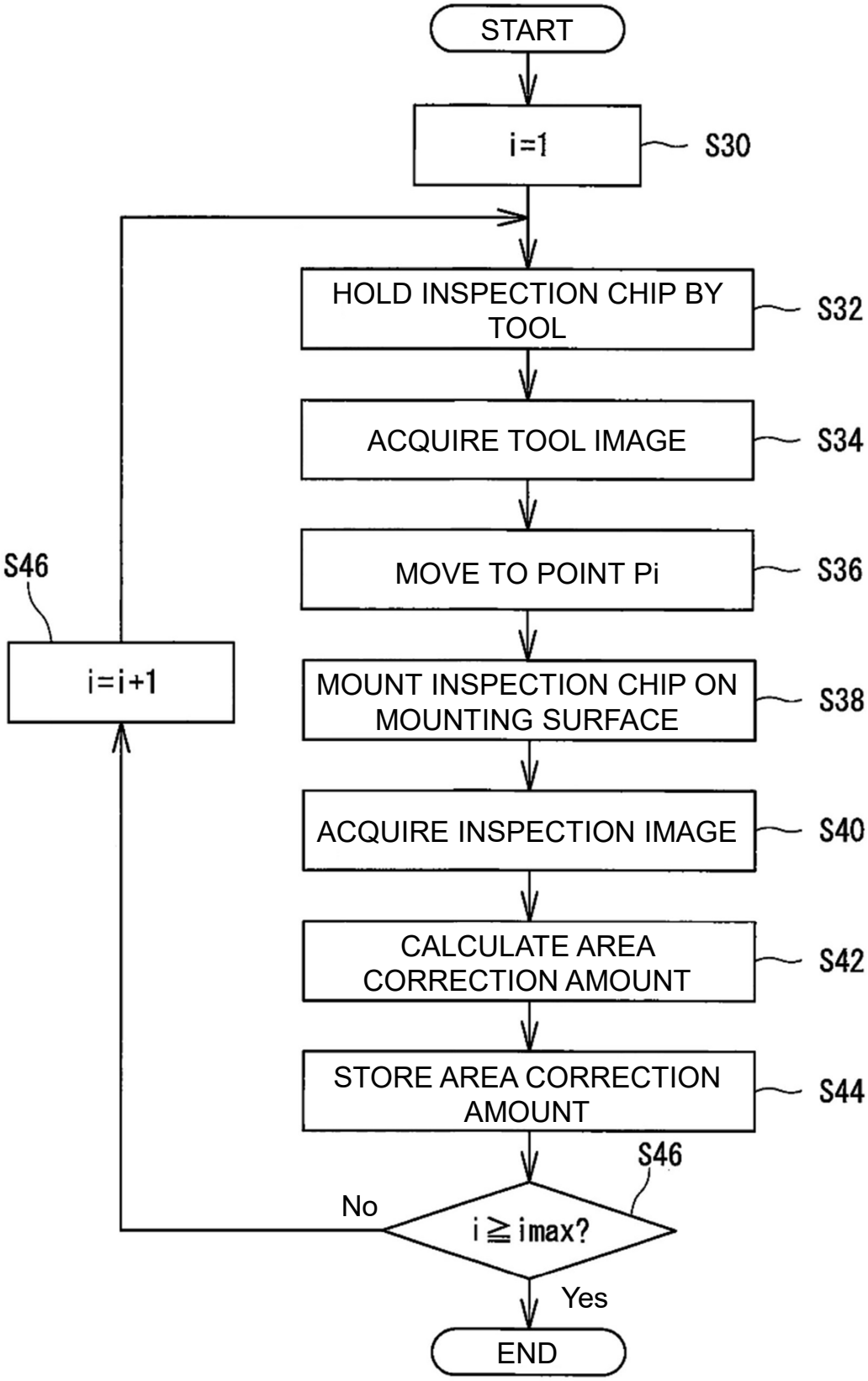
START
i=1
S30
HOLD INSPECTION CHIP BY TOOL
S32
ACQUIRE TOOL IMAGE
S34
MOVE TO POINT Pi
S36
MOUNT INSPECTION CHIP ON MOUNTING SURFACE
S38
ACQUIRE INSPECTION IMAGE
S40
CALCULATE AREA CORRECTION AMOUNT
S42
STORE AREA CORRECTION AMOUNT
S44
S46
i≧imax?
No
Yes
S46
i=i+1
END

FIG. 6

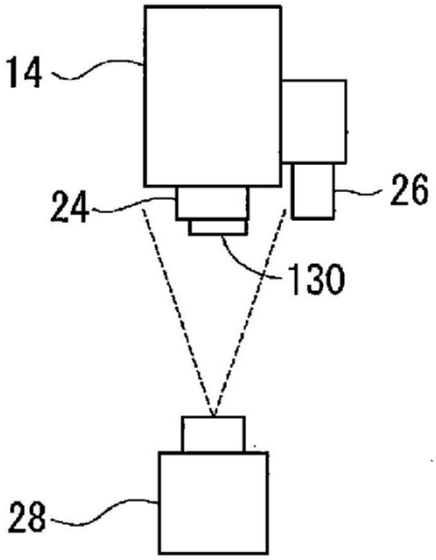

FIG. 7A

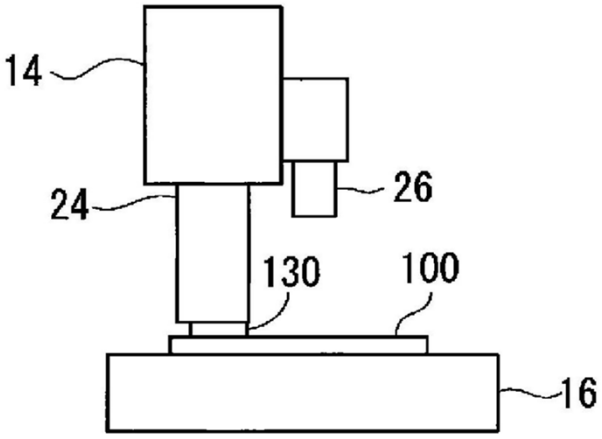

FIG. 7B

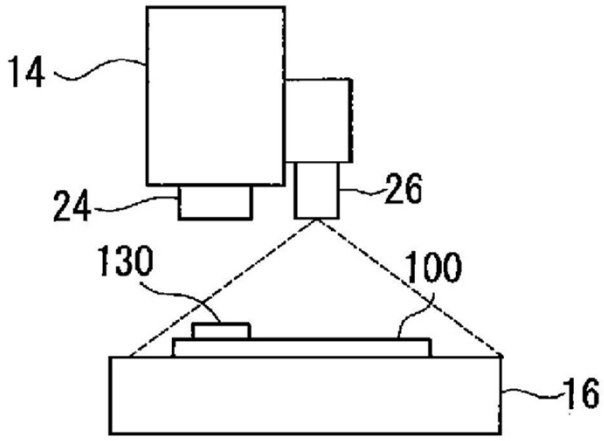

FIG. 7C

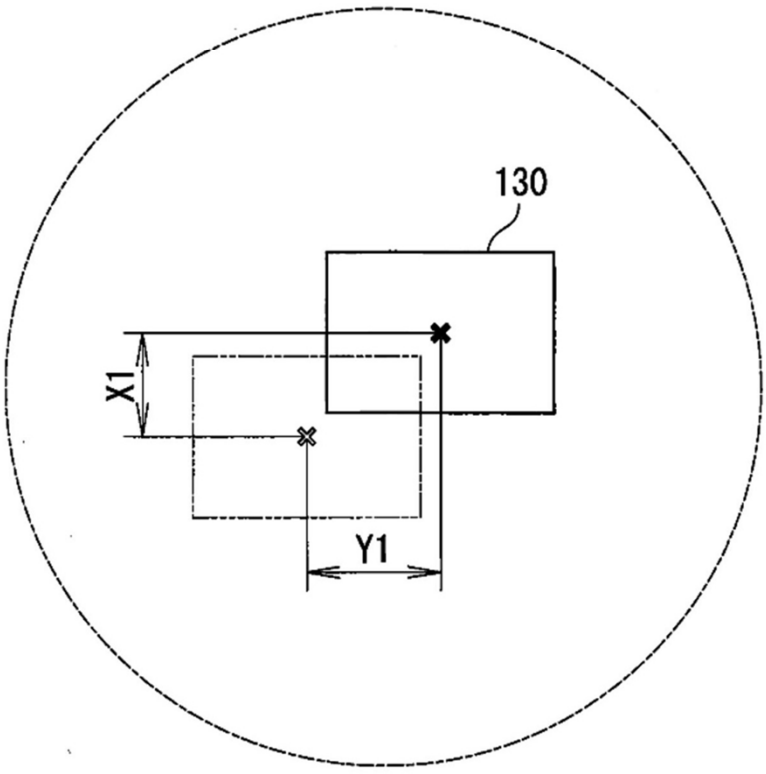

FIG. 8

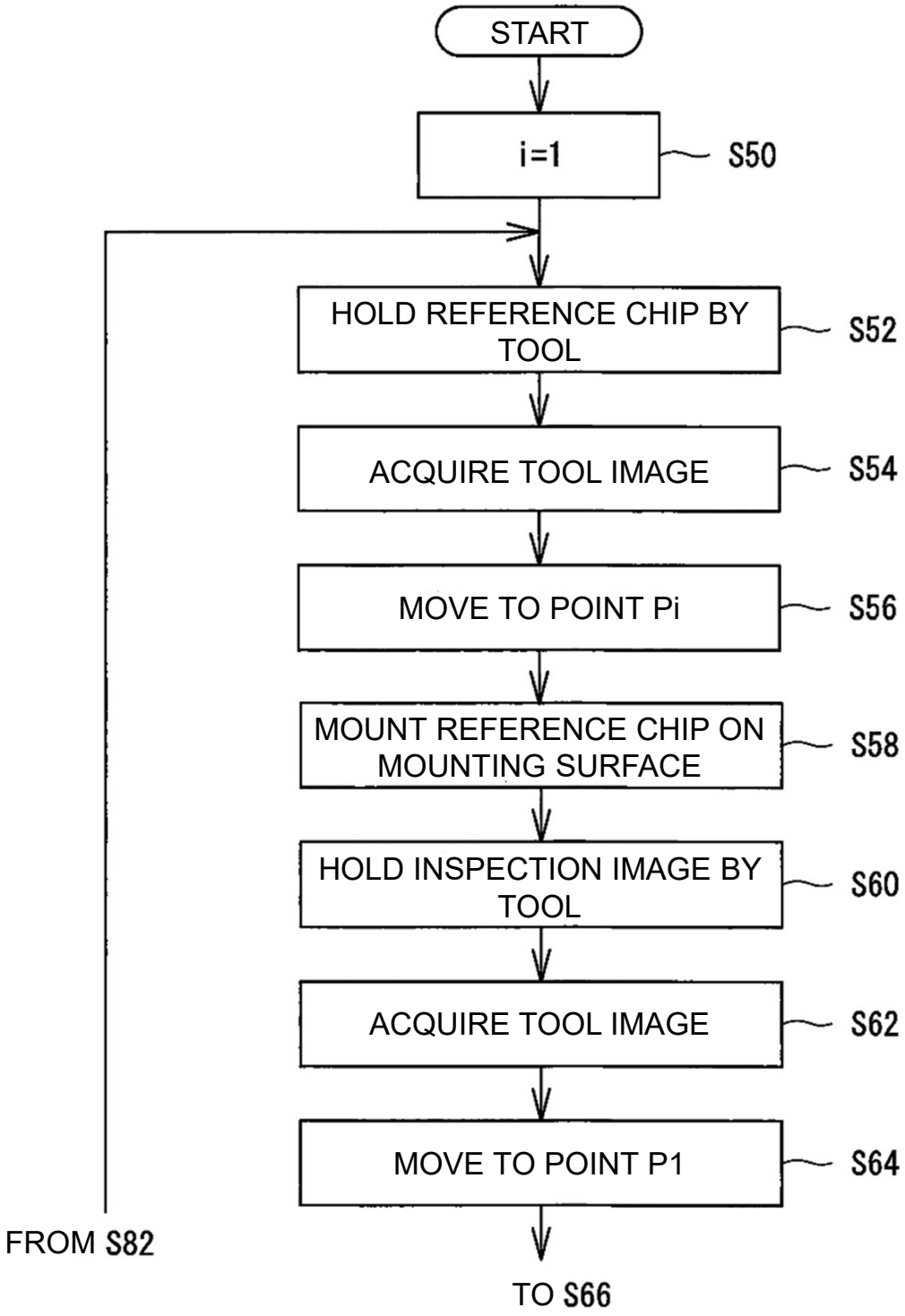
START
i=1
S50
HOLD REFERENCE CHIP BY TOOL
S52
ACQUIRE TOOL IMAGE
S54
MOVE TO POINT Pi
S56
MOUNT REFERENCE CHIP ON MOUNTING SURFACE
S58
HOLD INSPECTION IMAGE BY TOOL
S60
ACQUIRE TOOL IMAGE
S62
MOVE TO POINT P1
S64
FROM S82
TO S66

FIG. 9

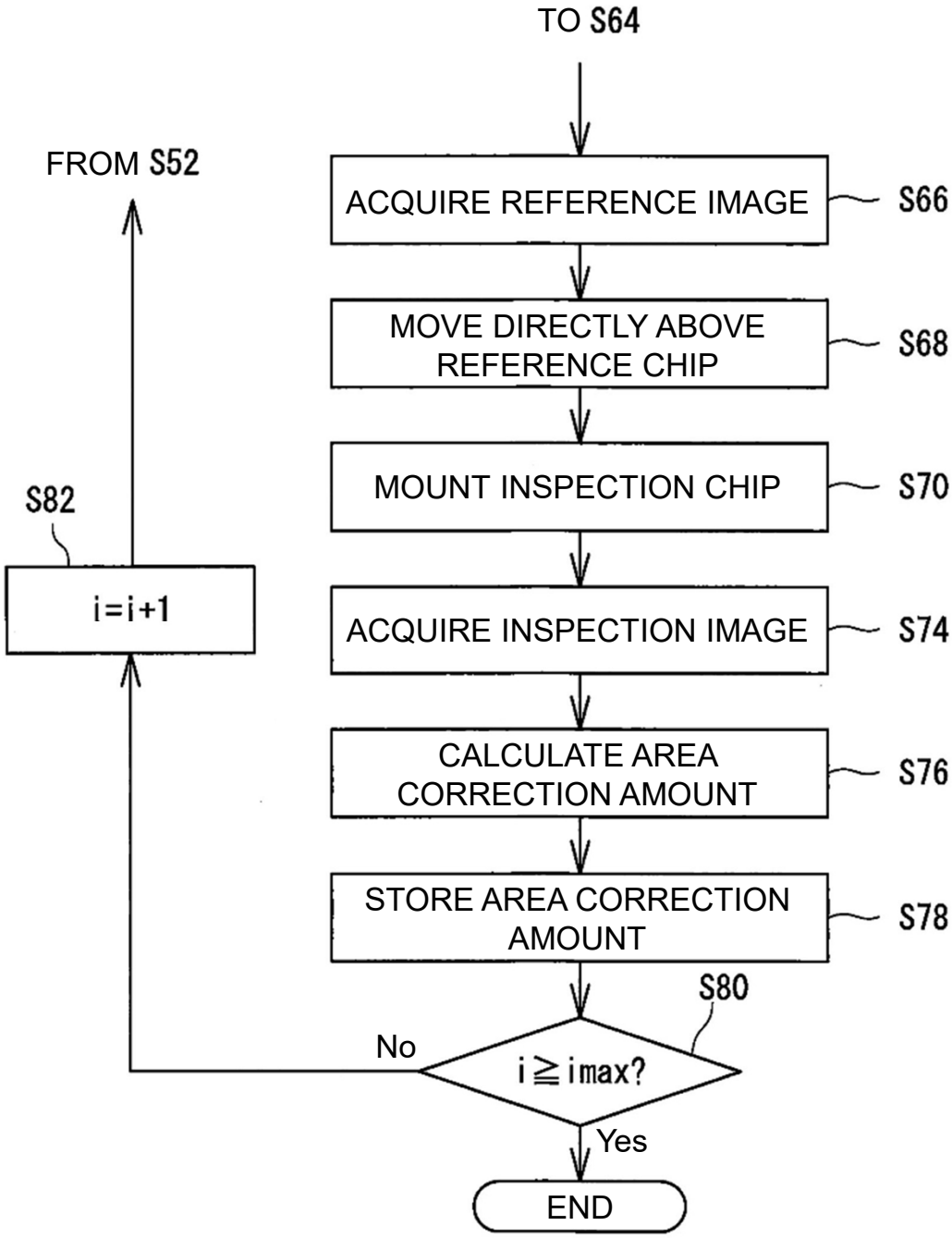
TO S64
FROM S52
ACQUIRE REFERENCE IMAGE
S66
MOVE DIRECTLY ABOVE REFERENCE CHIP
S68
MOUNT INSPECTION CHIP
S70
ACQUIRE INSPECTION IMAGE
S74
CALCULATE AREA CORRECTION AMOUNT
S76
STORE AREA CORRECTION AMOUNT
S78
S80
i≧imax?
No
Yes
END
S82
i=i+1

FIG. 10

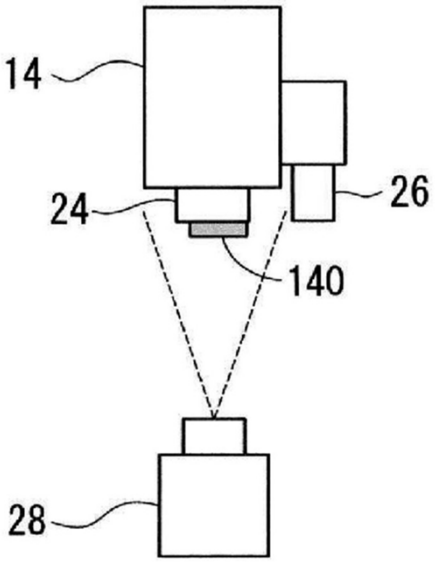

FIG. 11A

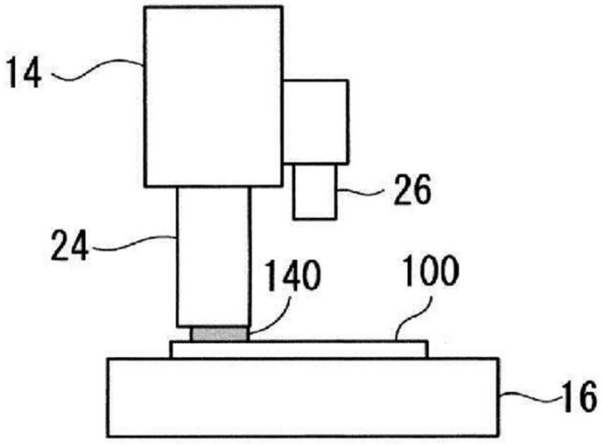

FIG. 11B

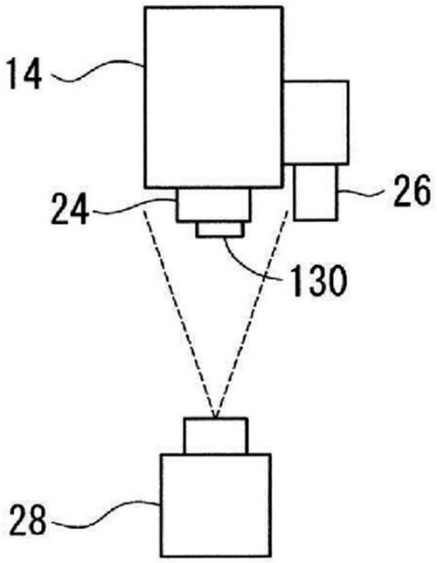

FIG. 11C

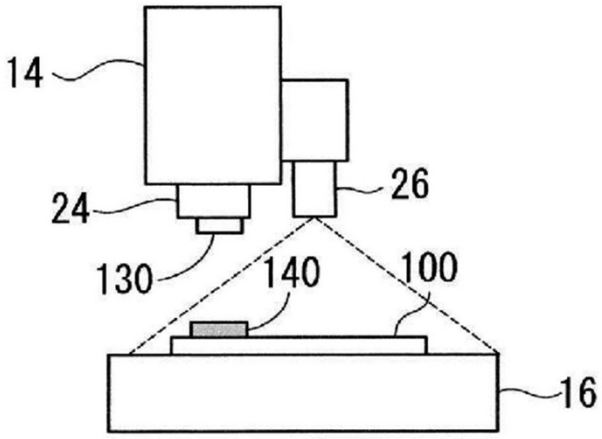

FIG. 12A

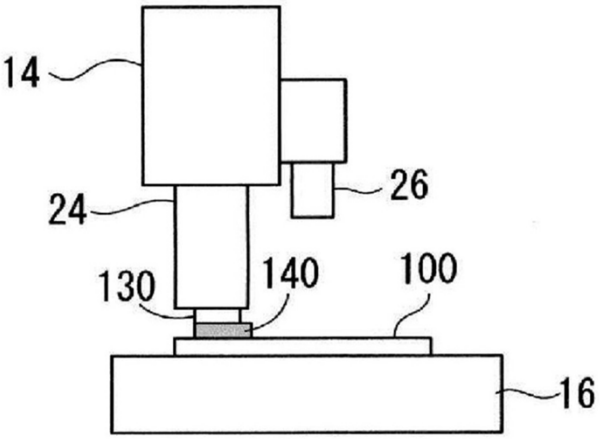

FIG. 12B

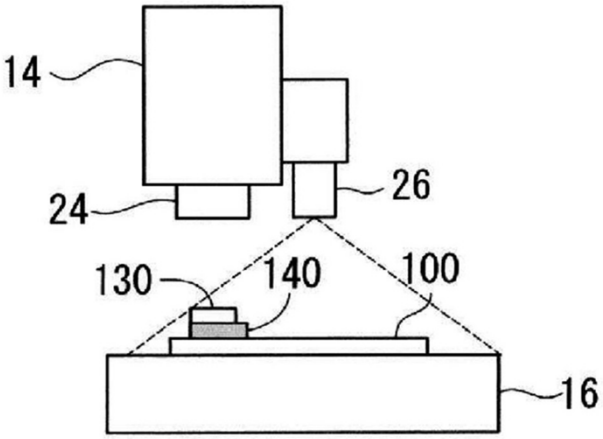

FIG. 12C

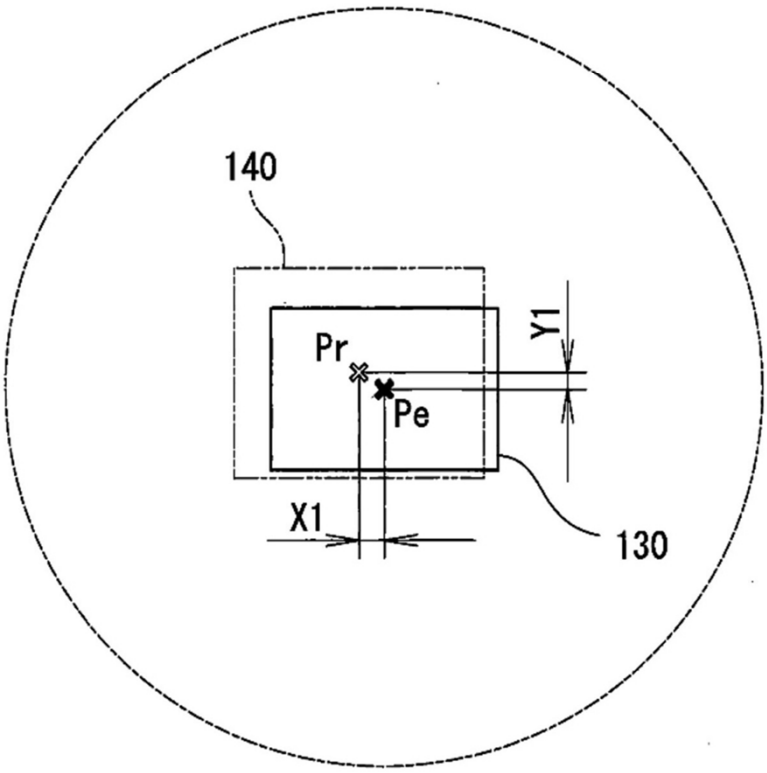

FIG. 13